

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Akiharu MIYANAGA et al. Art Unit : 2818
Serial No. : 10/667,899 Examiner : David Vu
Filed : September 23, 2003 Conf. No. : 8644
Title : SEMICONDUCTOR DEVICE AND METHOD OF MANUFACTURING THE
SAME

MAIL STOP RCE

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Applicants request consideration of the references listed on the attached PTO-1449 form.
Copies of any of the listed U.S. patents can be provided upon request.

This filing is being made with the filing of a Request for Continued Examination. No fee
is required.

Respectfully submitted,

Date: 2/23/07



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Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 07977-254003	Application No. 10/667,899
Information Disclosure Statement by Applicant (Use several sheets if necessary)		Applicant Akiharu MIYANAGA et al.	
		Filing Date September 23, 2003	Group Art Unit 2818
(37 CFR §1.98(b))			

U.S. Patent Documents

Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	6,251,733	06/26/2001	YAMAZAKI			04/07/2000
	AB	6,420,759	07/16/2002	YAMAZAKI et al.			12/28/2000
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Foreign Patent Documents or Published Foreign Patent Applications

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	AM							
	AN							
	AO							
	AP							
	AQ							

Other Documents (Include Author, Title, Date, and Place of Publication)

Examiner Initial	Desig. ID	Document
	AR	
	AS	
	AT	
	AU	

Examiner Signature	Date Considered
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	